

#### PATENT APPLICATION

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

K. GOTOH et al.

Atty. Docket No. 100021-00074

Serial No.: 10/082,055

**Examiner: Not Assigned** 

Filed: February 26, 2002

Art Unit: Not Assigned

For: TEST CIRCUIT AND SEMICONDUCTOR INTEGRATED CIRCUIT EFFECTIVELY CARRYING OUT VERIFICATION OF CONNECTION OF NODES

### **INFORMATION DISCLOSURE STATEMENT**

Director of the U.S. PTO P.O. Box 1450 Alexandria, VA 22313-1450

February 13, 2004

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Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the information item(s) listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each item(s) is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the item(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

| merits | This Information Disclosure Statement is being filed (a) within three months U.S. filing date, OR (b) before the mailing date of a first Office Action on the in the present application, OR (c) accompanies a Request for Continued mation. No certification or fee is required.   |
|--------|---|
|        | This Information Disclosure Statement is being filed more than three months he U.S. filing date AND after the mailing date of the first Office Action on the , but before the mailing date of a Final Rejection or Notice of Allowance.   |
|        | a. I hereby certify that each item of information contained in this Information Disclosure Statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement. 37 CFR §1.97(e)(1).  |
|        | b. I hereby certify that no item of information in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to my knowledge after making reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this Information Disclosure Statement. 37 CFR §1.97(e)(2). |

|             |                                      | c. A check in the amount of \$180.00 in payment of the fee under 37 CFR §1.17(p). Please charge any fee deficiency or credit any overpayment to Deposit Account No. 01-2300 as needed to ensure consideration of the disclosed information.   |
|-------------|--------------------------------------|---|
|             | Allowa<br>the Inf<br>amour<br>charge | This Information Disclosure Statement is being filed more than three months ne U.S. filing date and after the mailing date of a Final Rejection or Notice of nce, but before payment of the Issue Fee. Applicant(s) hereby petition(s) that ormation Disclosure Statement be considered. Attached is our check in the at of \$180.00 in payment of the petition fee under 37 CFR §1.17(i)(1). Please any fee deficiency or credit any overpayment to Deposit Account No. 01-2300 aded to ensure consideration of the disclosed information. |
|             |                                      | a. I hereby certify that each item of information contained in this Information Disclosure Statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement. 37 CFR §1.97(e)(1).  |
|             |                                      | b. I hereby certify that no item of information in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to my knowledge after making reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this Information Disclosure Statement. 37 CFR §1.97(e)(2).   |
| $\boxtimes$ | 4.<br>langua<br>informa              | The references were cited in a counterpart foreign application. An English ge version of the foreign search report is attached for the Examiner's ation.  |

Respectfully submitted,

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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

| ATTY. DOCKET NO. | SERIAL NO. |
|------------------|------------|
| 100021-00074     | 10/082,055 |
| APPLICANT `      |            |

# LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

| Gotoh et al.      |              |
|-------------------|--------------|
| FILING DATE       | GROUP        |
| February 26, 2002 | Not Assigned |

EB 1 3 2004

U.S. PATENT DOCUMENTS

|          |    |                 | U.S. P  | ATENT DOCUMENTS   |       |               |                |
|----------|----|-----------------|---------|-------------------|-------|---------------|----------------|
| EXAMINER |    | DOCUMENT<br>NO. | DATE    | NAME              | CLASS | SUB-<br>CLASS | FILING<br>DATE |
|          | AA | 4,698,830       | 10/6/87 | Barzilai et al.   | 377   | 19            |                |
|          | AB | 5,299,136       | 3/29/94 | Babakanian et al. | 364   | 488           |                |
|          | AC | 5,287,386       | 2/15/94 | Wade et al.       | 375   | 36            |                |
|          | AD |                 |         |                   |       |               |                |
|          | AE |                 |         |                   |       |               |                |
|          | AF |                 |         |                   |       |               |                |

#### **FOREIGN PATENT DOCUMENTS**

|   | DOCUMENT<br>NO. | DATE | COUNTRY | CLASS | SUB-<br>CLASS | TRA<br>YES | NSLAT | ION<br>PART. |
|---|-----------------|------|---------|-------|---------------|------------|-------|--------------|
| , | AG              |      |         |       |               |            |       |              |
| , | АН              |      |         |       |               |            |       |              |
|   | AI              |      |         |       |               |            |       |              |
|   | AJ              |      |         |       |               |            |       |              |
| , | AK              |      |         |       |               |            |       |              |
|   | AL              |      |         |       |               |            |       |              |

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

| АМ | "Integration of IEEE 1149.1 with Mixed ECL, TTL, and Differential Logic Signals", John Andrews, 1993 IEEE, pgs. 355-360. |
|----|--|
| AN | "Built-In Parametric Test For Controlled Impedance I/Os", Tord Haulin, 1997 IEEE, pgs. 123-128.                          |
| AO |  |

| EXAMINER   |  | DATE CONSIDERED   |  |  |
|------------|--|---|--|--|
| *EXAMINER: | Initial if reference considered, whether or not citation is in | n conformance with MPEP 609; Draw line through citation if not in |  |  |